

Philips Semiconductors

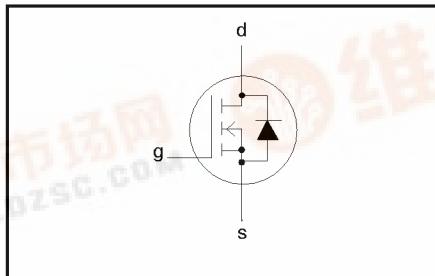
Product specification

PowerMOS transistors Avalanche energy rated

PHP12N50E

FEATURES

- Repetitive Avalanche Rated
- Fast switching
- Stable off-state characteristics
- High thermal cycling performance
- Low thermal resistance

SYMBOL**QUICK REFERENCE DATA**

$V_{DSS} = 500 \text{ V}$
 $I_D = 11.6 \text{ A}$
 $R_{DS(ON)} \leq 0.52 \Omega$

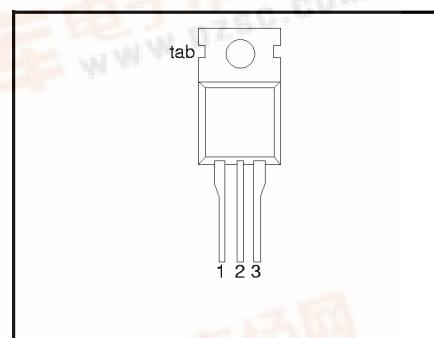
GENERAL DESCRIPTION

N-channel, enhancement mode field-effect power transistor, intended for use in off-line switched mode power supplies, T.V. and computer monitor power supplies, d.c. to d.c. converters, motor control circuits and general purpose switching applications.

The PHP11N50E is supplied in the SOT78 (TO220AB) conventional leaded package.

PINNING

PIN	DESCRIPTION
1	gate
2	drain
3	source
case	drain

SOT78 (TO220AB)**LIMITING VALUES**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DSS}	Drain-source voltage	$T_j = 25^\circ\text{C} \text{ to } 150^\circ\text{C}$	-	500	V
V_{DGR}	Drain-gate voltage	$T_j = 25^\circ\text{C} \text{ to } 150^\circ\text{C}; R_{GS} = 20 \text{ k}\Omega$	-	500	V
V_{GS}	Gate-source voltage		-	± 30	V
I_D	Continuous drain current	$T_{mb} = 25^\circ\text{C}; V_{GS} = 10 \text{ V}$	-	11.6	A
I_{DM}		$T_{mb} = 100^\circ\text{C}; V_{GS} = 10 \text{ V}$	-	7.3	A
P_D	Pulsed drain current	$T_{mb} = 25^\circ\text{C}$	-	46	A
T_j, T_{stg}	Total dissipation	$T_{mb} = 25^\circ\text{C}$	-	167	W
	Operating junction and storage temperature range	$T_{mb} = 25^\circ\text{C}$	-55	150	$^\circ\text{C}$

AVALANCHE ENERGY LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
E_{AS}	Non-repetitive avalanche energy	Unclamped inductive load, $I_{AS} = 11.3 \text{ A}$; $t_p = 0.2 \text{ ms}$; T_j prior to avalanche = 25°C ; $V_{DD} \leq 50 \text{ V}$; $R_{GS} = 50 \Omega$; $V_{GS} = 10 \text{ V}$	-	732	mJ
E_{AR}	Repetitive avalanche energy ¹	$I_{AR} = 11.6 \text{ A}$; $t_p = 2.5 \mu\text{s}$; T_j prior to avalanche = 25°C ; $R_{GS} = 50 \Omega$; $V_{GS} = 10 \text{ V}$	-	18	mJ
I_{AS}, I_{AR}	Repetitive and non-repetitive avalanche current		-	11.6	A

¹ pulse width and repetition rate limited by T_j max.

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THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th\ j\text{-}mb}$	Thermal resistance junction to mounting base		-	-	0.75	K/W
$R_{th\ j\text{-}a}$	Thermal resistance junction to ambient		-	60	-	K/W

ELECTRICAL CHARACTERISTICS

$T_j = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}; I_D = 0.25\text{ mA}$	500	-	-	V
$\Delta V_{(BR)DSS} / \Delta T_j$	Drain-source breakdown voltage temperature coefficient	$V_{DS} = V_{GS}; I_D = 0.25\text{ mA}$	-	0.1	-	%/K
$R_{DS(ON)}$	Drain-source on resistance	$V_{GS} = 10\text{ V}; I_D = 5.5\text{ A}$	-	0.47	0.52	Ω
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 0.25\text{ mA}$	2.0	3.0	4.0	V
g_{fs}	Forward transconductance	$V_{DS} = 30\text{ V}; I_D = 5.5\text{ A}$	4	6.5	-	S
I_{DSS}	Drain-source leakage current	$V_{DS} = 500\text{ V}; V_{GS} = 0\text{ V}$	-	1	25	μA
I_{GSS}	Gate-source leakage current	$V_{DS} = 400\text{ V}, V_{GS} = 0\text{ V}; T_j = 125^\circ\text{C}$	-	60	500	μA
		$V_{GS} = \pm 30\text{ V}; V_{DS} = 0\text{ V}$	-	10	200	nA
$Q_{g(\text{tot})}$	Total gate charge	$I_D = 11\text{ A}; V_{DD} = 400\text{ V}; V_{GS} = 10\text{ V}$	-	75	100	nC
Q_{gs}	Gate-source charge		-	7	12	nC
Q_{gd}	Gate-drain (Miller) charge		-	39	55	nC
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 250\text{ V}; R_D = 22\Omega; R_G = 5.6\Omega$	-	11	-	ns
t_r	Turn-on rise time		-	38	-	ns
$t_{d(off)}$	Turn-off delay time		-	92	-	ns
t_f	Turn-off fall time		-	40	-	ns
L_d	Internal drain inductance	Measured from tab to centre of die	-	3.5	-	nH
L_d	Internal drain inductance	Measured from drain lead to centre of die	-	4.5	-	nH
L_s	Internal source inductance	Measured from source lead to source bond pad	-	7.5	-	nH
C_{iss}	Input capacitance	$V_{GS} = 0\text{ V}; V_{DS} = 25\text{ V}; f = 1\text{ MHz}$	-	1326	-	pF
C_{oss}	Output capacitance		-	182	-	pF
C_{rss}	Feedback capacitance		-	96	-	pF

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

$T_j = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_s	Continuous source current (body diode)	$T_{mb} = 25^\circ\text{C}$	-	-	11.6	A
I_{SM}	Pulsed source current (body diode)	$T_{mb} = 25^\circ\text{C}$	-	-	46	A
V_{SD}	Diode forward voltage	$I_s = 11\text{ A}; V_{GS} = 0\text{ V}$	-	-	1.2	V
t_{rr}	Reverse recovery time	$I_s = 11\text{ A}; V_{GS} = 0\text{ V}; dI/dt = 100\text{ A}/\mu\text{s}$	-	630	-	ns
Q_{rr}	Reverse recovery charge		-	6.9	-	μC

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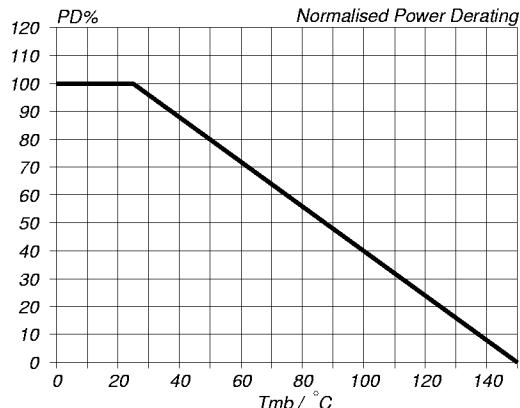


Fig.1. Normalised power dissipation.
 $PD\% = 100 \cdot P_D / P_{D, 25^\circ C} = f(T_{mb})$

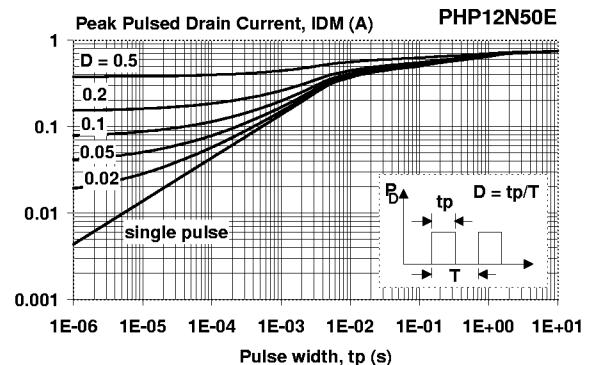


Fig.4. Transient thermal impedance.
 $Z_{th,j-mb} = f(t_p); \text{parameter } D = t_p/T$

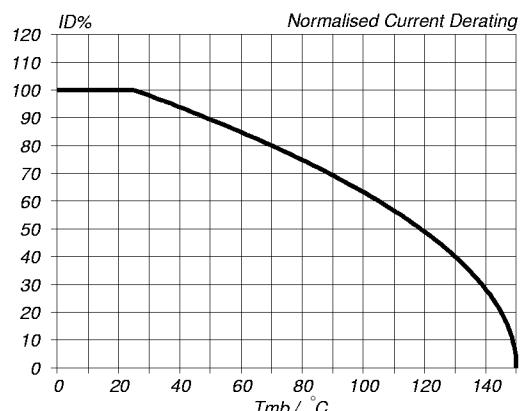


Fig.2. Normalised continuous drain current.
 $ID\% = 100 \cdot I_D / I_{D, 25^\circ C} = f(T_{mb}); \text{conditions: } V_{GS} \geq 10 \text{ V}$

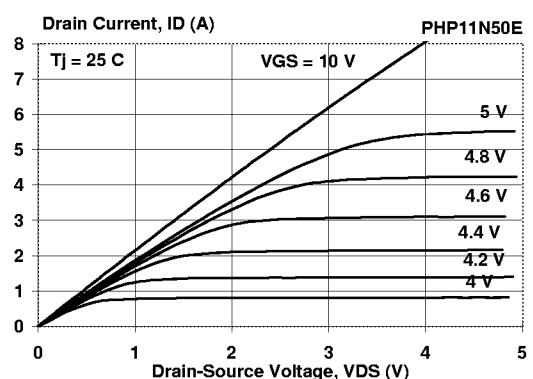


Fig.5. Typical output characteristics.
 $I_D = f(V_{DS}); \text{parameter } V_{GS}$

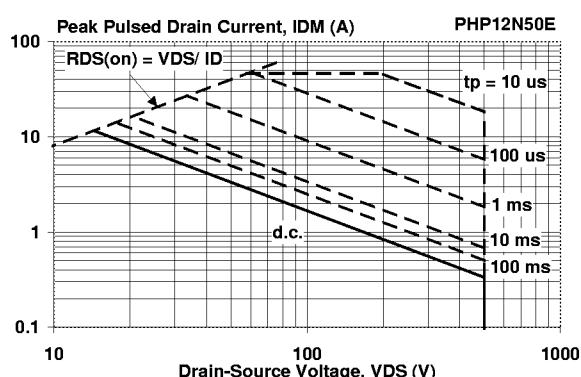


Fig.3. Safe operating area. $T_{mb} = 25^\circ C$
 $I_D \text{ & } I_{DM} = f(V_{DS}); I_{DM} \text{ single pulse; parameter } t_p$

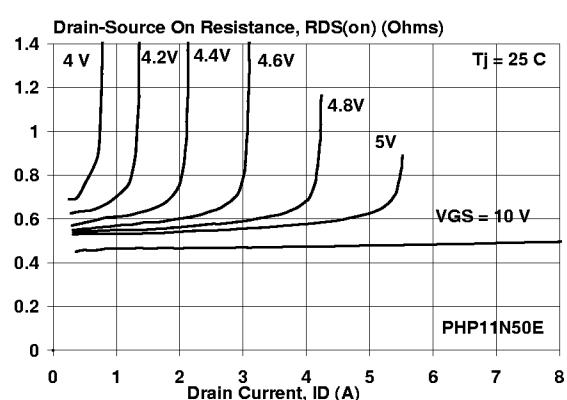


Fig.6. Typical on-state resistance.
 $R_{DS(ON)} = f(I_D); \text{parameter } V_{GS}$

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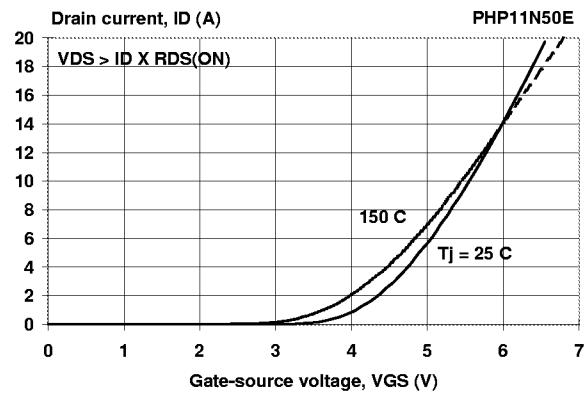


Fig. 7. Typical transfer characteristics.
 $I_D = f(V_{GS})$; parameter T_j

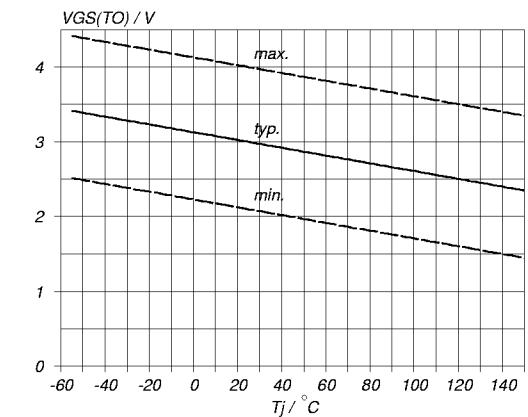


Fig. 10. Gate threshold voltage.
 $V_{G_{TO}} = f(T_j)$; conditions: $I_D = 0.25$ mA; $V_{DS} = V_{GS}$

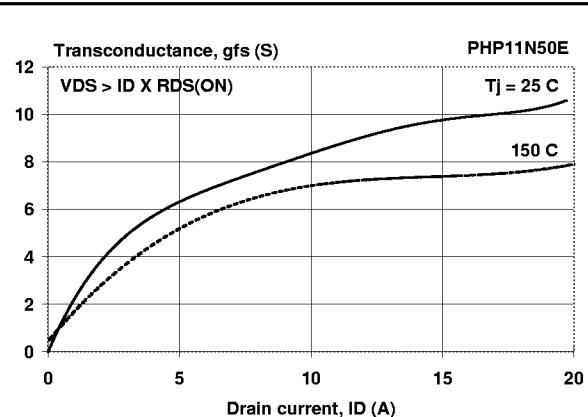


Fig. 8. Typical transconductance.
 $g_{f_s} = f(I_D)$; parameter T_j

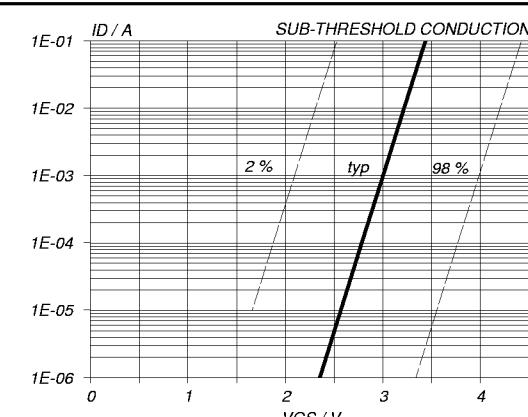


Fig. 11. Sub-threshold drain current.
 $I_D = f(V_{GS})$; conditions: $T_j = 25$ °C; $V_{DS} = V_{GS}$

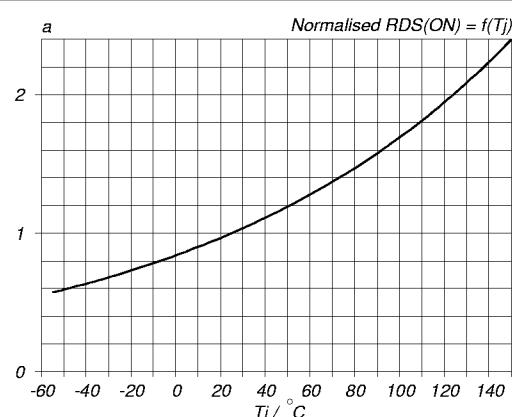


Fig. 9. Normalised drain-source on-state resistance.
 $a = R_{DS(ON)}/R_{DS(ON)25\text{ }^{\circ}\text{C}} = f(T_j)$; $I_D = 5.5$ A; $V_{GS} = 10$ V

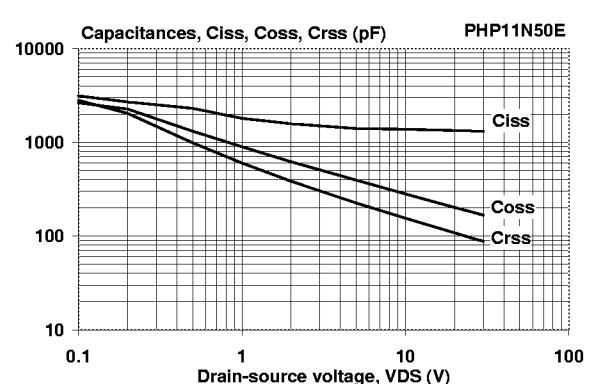


Fig. 12. Typical capacitances, C_{iss} , C_{oss} , C_{rss} .
 $C = f(V_{DS})$; conditions: $V_{GS} = 0$ V; $f = 1$ MHz

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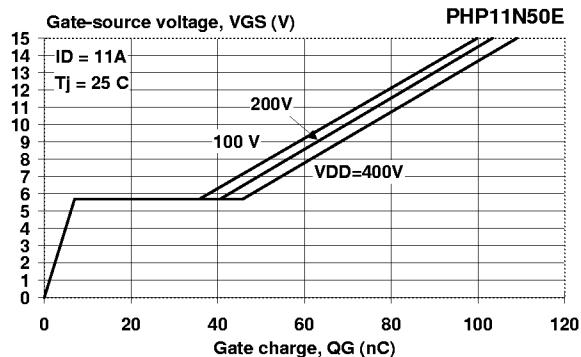


Fig.13. Typical turn-on gate-charge characteristics.
 $V_{GS} = f(Q_G)$; parameter V_{DS}

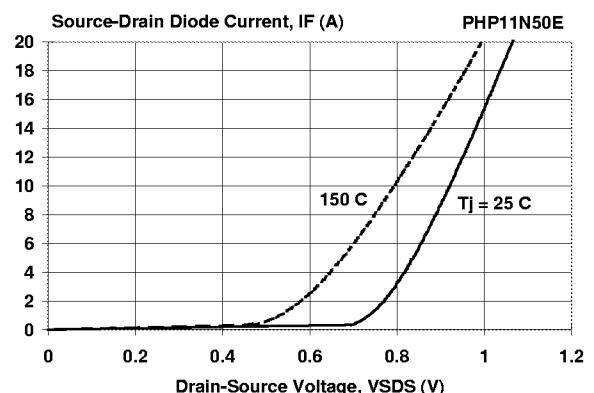


Fig.16. Source-Drain diode characteristic.
 $I_F = f(V_{DS})$; parameter T_J

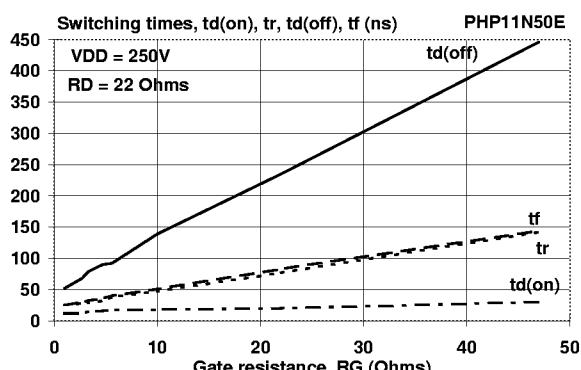


Fig.14. Typical switching times; $t_{d(on)}$, t_r , $t_{d(off)}$, $t_f = f(R_G)$

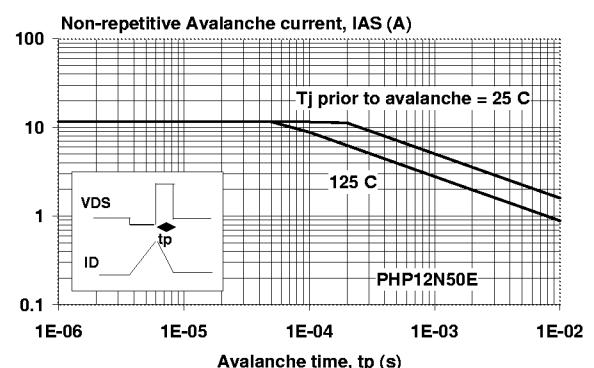


Fig.17. Maximum permissible non-repetitive avalanche current (I_{AS}) versus avalanche time (t_p); unclamped inductive load

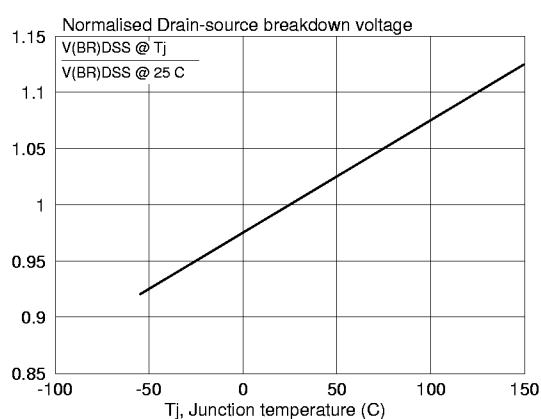


Fig.15. Normalised drain-source breakdown voltage;
 $V_{(BR)DSS}/V_{(BR)DSS} 25\text{ }^{\circ}\text{C} = f(T_j)$

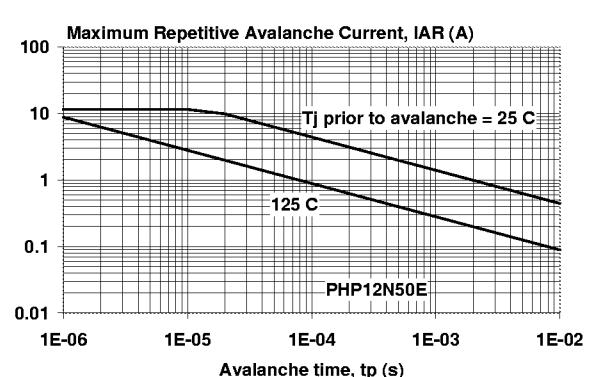


Fig.18. Maximum permissible repetitive avalanche current (I_{AR}) versus avalanche time (t_p)

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Net Mass: 2 g

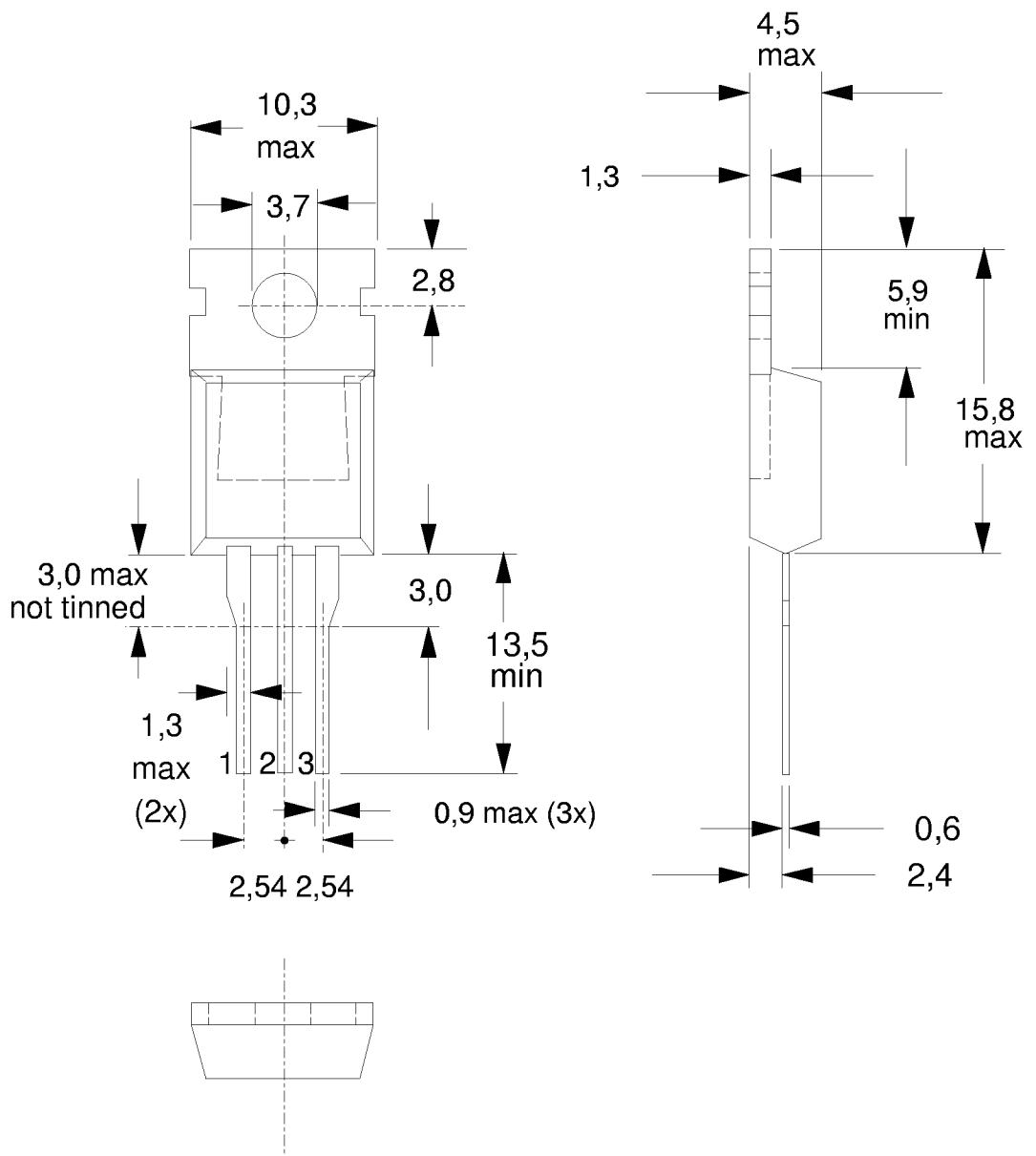


Fig.19. SOT78 (TO220AB); pin 2 connected to mounting base.

Notes

1. Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
2. Refer to mounting instructions for SOT78 (TO220) envelopes.
3. Epoxy meets UL94 V0 at 1/8".